




Erratum

Erratum: De Teresa, J.M. et al. Comparison between Focused Electron/Ion Beam-Induced Deposition at Room Temperature and under Cryogenic Conditions. *Micromachines* 2019, 10, 799

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In Section 3.1 (page 4) [1], on the fourth line, it says “C/cm²”. It should be changed to “μC/cm²”. The editorial office would like to apologize for any inconvenience caused to the authors and readers.

References

1. De Teresa, J.M.; Orús, P.; Córdoba, R.; Philipp, P. Comparison between Focused Electron/Ion Beam-Induced Deposition at Room Temperature and under Cryogenic Conditions. *Micromachines* **2019**, *10*, 799. [[CrossRef](#)] [[PubMed](#)]



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